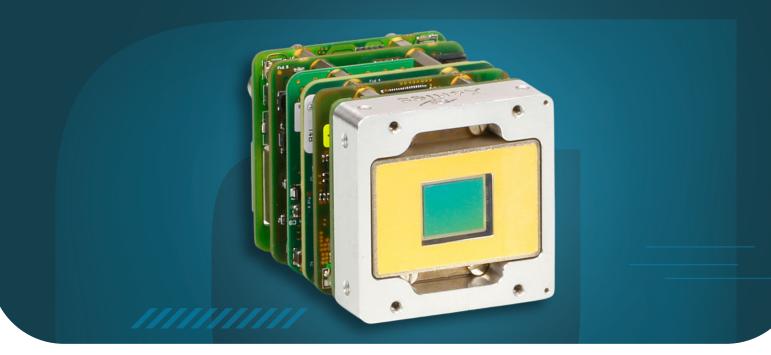
SWIR InGaAs MODULE FOR SHORT EXPOSURES



XSW 320 Gated Series

Area-scan SWIR cooled module with 320 x 256 resolution



SWIR InGaAs MODULE FOR SHORT EXPOSURES

KEY FEATURES

- ◆ Extremely short 100 ns integration time
- ◆ CameraLink, GigE Vision or QTE Samtec interfacing options
- ◆ Small SWIR area-scan module

The XSW 320 Gated series is based on an inhouse developed temperature stabilised InGaAs detector with a 320 x 256 pixel resolution. The XSW 320 Gated modules are able to provide maximum frame rates up to 400 Hz. The exposure time of the sensor is configurable from 100 ns up to 1 ms in steps of 100 ns, or from 1 ms to 40 ms. The module comes with either CameraLink, GigE Vision or QTE Samtec interface.



XSW 320 Gated Series





KEY PERFORMANCES

Image format/Pixel pitch	320 X 256 pixels/20 μm
Detector type	InGaAs photodiode array with CTIA ROIC
Integration type	Snapshot - global shutter
Sensor temperature stabilization	TE cooler
Spectral range	900 nm - 1700 nm
Max frame rate (full frame)	400 Hz
Power consumption	2.5 W (no TE cooler); 2.8 W (no TE cooler);
	4 W (no TE cooler)
Power supply voltage	DC 12V

FUNCTIONS & INTERFACES

Command and control	CameraLink or GigE Vision or QTE Samtec
Connector trigger	SMA (CL and GigE)
Camera dimensions (width x height x length)	45 mm x 45 mm x 56 mm (CL), 45 mm x 45 mm x 65 mm (GigE), 45 m x 45 mm x 52 mm (16 bit DV)
Optical interface (optional)	C-mount or M42
Camera weight	129 g (CL); 165 g (GigE); 122 g (16bit DV)

PRODUCT SELECTOR GUIDE

XEN-000594 (XSW 320 CL Gated)	XEN-000593 (XSW 320 GigE Gated)

XEN-000596 (XSW 320 16bitDV Gated)



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xenics.com

